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## \*BIBDATASHEET\*

**Bib Data Sheet** 

**CONFIRMATION NO. 2727** 

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SERIAL NUMB! 10/647,506	ER	FILING DATE 08/26/2003	CLASS 324		GROI	JP ART UNIT 2829		D	TTORNEY OCKET NO.	
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APPLICANTS										
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** CONTINUING DATA **********************************										
"FOREIGN APPLICATIONS "Verilal Jak										
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 11/18/2003										
Foreign Priority claimed					SH	IEETS	TOTAL		INDEPENDENT	
met  Verified and  Acknowledged				COUNTRY JAPAN	DRA	AWING CLA		IMS 5 12	CLAIMS 26 8	
ADDRESS STEVENS, DAVIS, MILLER & MOSHER, L.L.P. Suite 850 1615 L Street, N.W. Washington , DC 20036										
TITLE Semiconductor integrated circuit and memory test method										
☐ All Fees										
						1.16 Fees (Filing)				
		S: Authority has been g			1.17 Fees ( Processing Ext. of time )					
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		•					Other_			